

Application/Control No.	Applicant(s)/Patent under Reexamination
10/500,656	TOYOOKA ET AL.
Examiner	Art Unit
Marlon A. Arce-Diaz	3611

SEARCHED				
Class	Subclass	Date	Examiner	
Update		4/26/2006	MAA	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
180	410,417	6/26/2006	MAA		
see h	nistory				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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